

Search Notes

Application/Control No.

10/760,317

Examiner

TAN X. DINH

Applicant(s)/Patent under
Reexamination

ISHII ET AL.

Art Unit

2627

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------------|-----------|----------|
| 369 | 13.12 13.11 | 2/27/2007 | T.D |
| 369 | 13.13 | 2/27/2007 | T.D |
| 369 | 13.2 | 2/27/2007 | T.D |
| 369 | 13.21 | 2/27/2007 | T.D |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| EAST (see search history printout) | 2/27/2007 | T.D |
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